

**IN THE UNITED STATES  
PATENT AND TRADEMARK OFFICE**

Appl. No. :  
Applicant(s) : DE JONG et al.  
Filed : Herewith  
TC/A.U. : 2857 (in parent)  
Examiner : Craig MILLER (in parent)  
Atty. Docket : N-17203-A

Title: CIRCUIT WITH INTERCONNECT TEST UNIT AND  
A METHOD OF TESTING INTERCONNECTS  
BETWEEN A FIRST AND A SECOND  
ELECTRONIC CIRCUIT

**PRELIMINARY AMENDMENT**

Mail Stop **Non-Fee Amendment**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Preliminary to examination of the above-referenced application, please amend  
the application as follows.

**This paper includes** (each beginning on a separate sheet):

- 1. Amendments to the specification;**
- 2. Amendments to the claims; and**
- 3. Remarks/Discussion of issues.**